



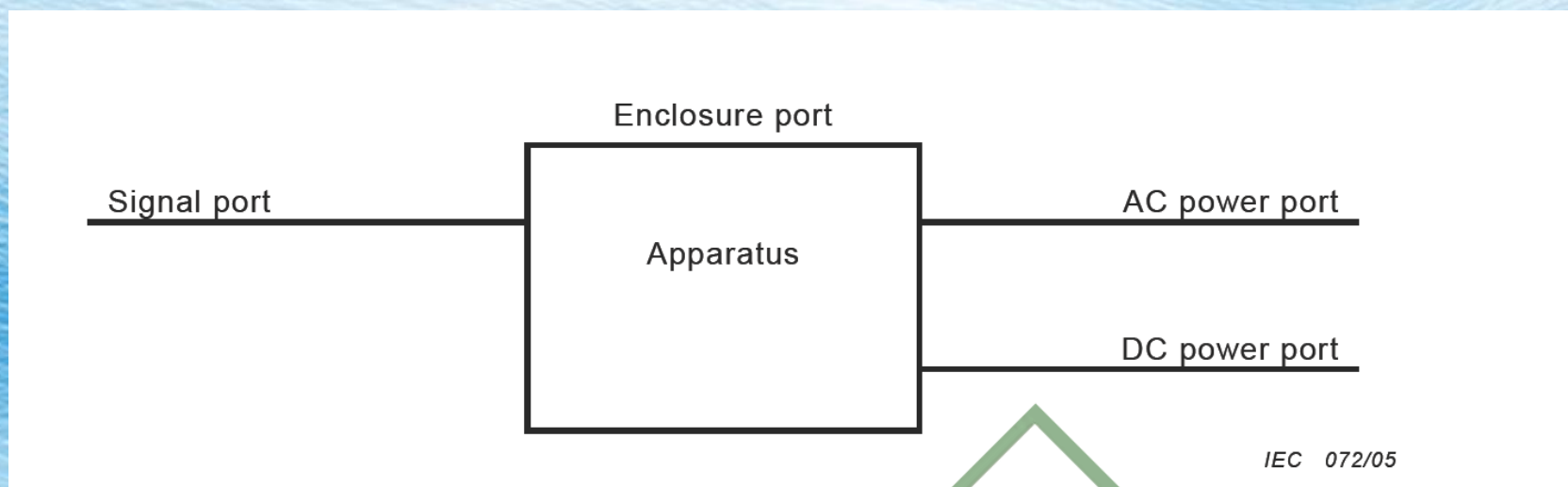
# Elektromagnetska kompatibilnost

## Metode ispitivanja uređaja

- Saša Gros
- 19.06.2012.
- Institut za elektrotehniku d.d.



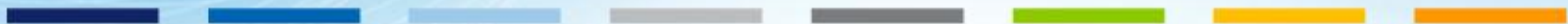
## Ispitivanja otpornosti uređaja na utjecaj smetnji



## Kriteriji izvedbe tijekom ispitivanja otpornosti

### Kriterij A:

Uređaj mora trajno raditi prema svojoj namjeni tijekom i nakon ispitivanja. Nije dozvoljena degradacija izvedbe ispod razine deklarirane od strane proizvođača, ukoliko se uređaj koristi prema namjeni. Ukoliko minimalna razina izvedbe nije određena od strane proizvođača, određuje se na temelju tehničke dokumentacije i mogućih očekivanja korisnika uređaja

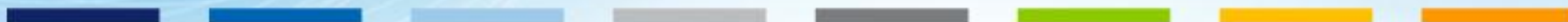




## Kriteriji izvedbe tijekom ispitivanja otpornosti

### Kriterij B:

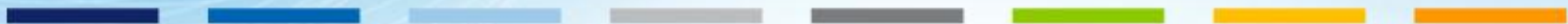
Uređaj mora trajno raditi prema svojoj namjeni nakon ispitivanja. Tijekom ispitivanja, dozvoljena je degradacija izvedbe ispod razine deklarirane od strane proizvođača. Nije dozvoljena promjena trenutnog radnog stanja ili pohranjenih podataka. Ukoliko minimalna razina izvedbe nije određena od strane proizvođača, određuje se na temelju tehničke dokumentacije i mogućih očekivanja korisnika uređaja



## Kriteriji izvedbe tijekom ispitivanja otpornosti

Kriterij C:

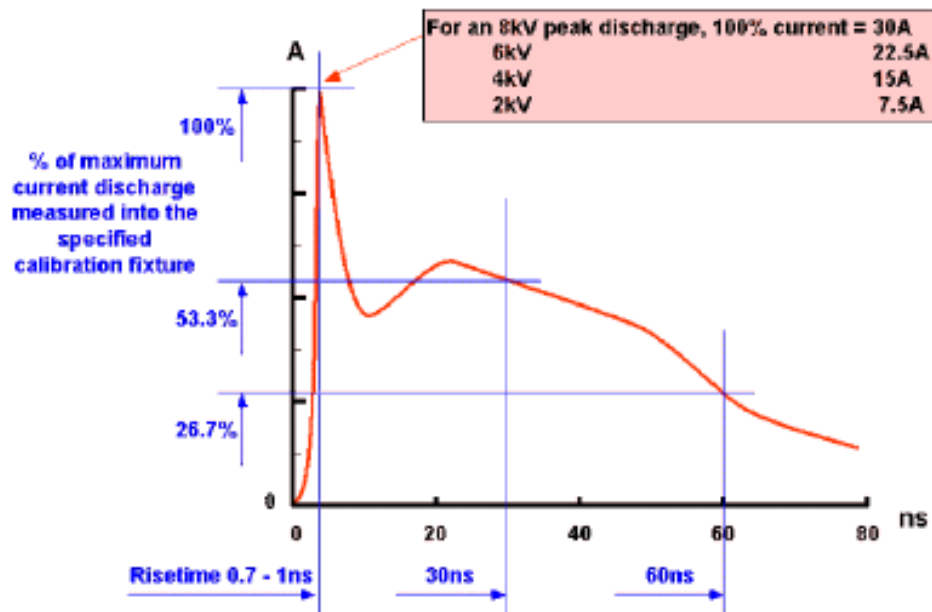
Dozvoljen je privremeni gubitak funkcija, uzimajući u obzir da su funkcije samo-oporavljive ili se mogu ponovno aktivirati uporabom kontrolnih tipki



# KONČAR

## ISPITIVANJE OTPORNOSTI NA ESD PREMA HRN EN 61000-4-2

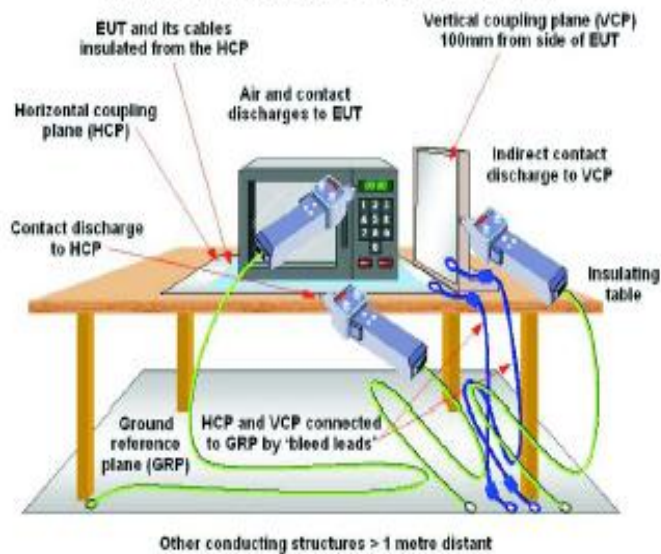
The standard EN 61000-4-2 current waveshape  
(from Figure 3 of EN 61000-4-2)



- *Ispitivanja naponom oba polariteta*
- *Vrijednosti : 2 kV, 4 kV, 6 kV, 8 kV, 15 kV*

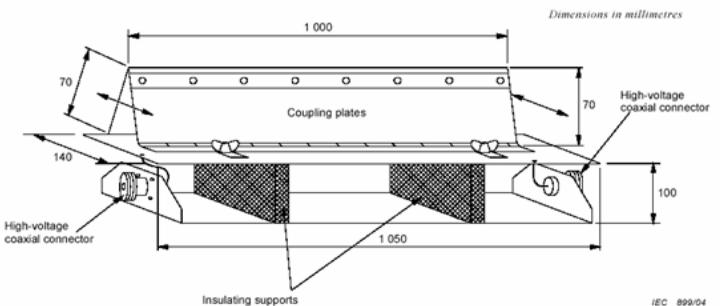
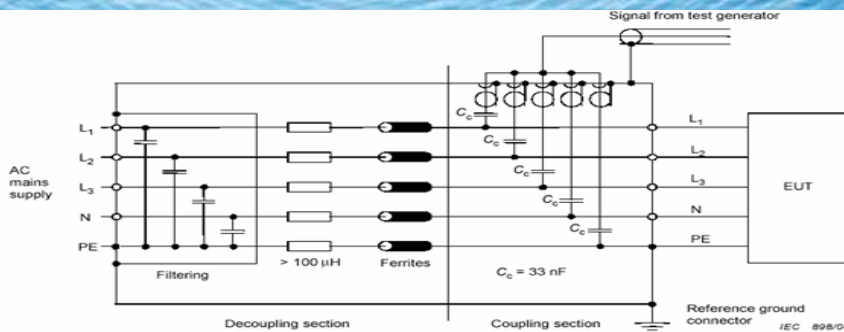


The test set-up for table-top products  
(adapted from Figure 5 of EN 61000-4-2)

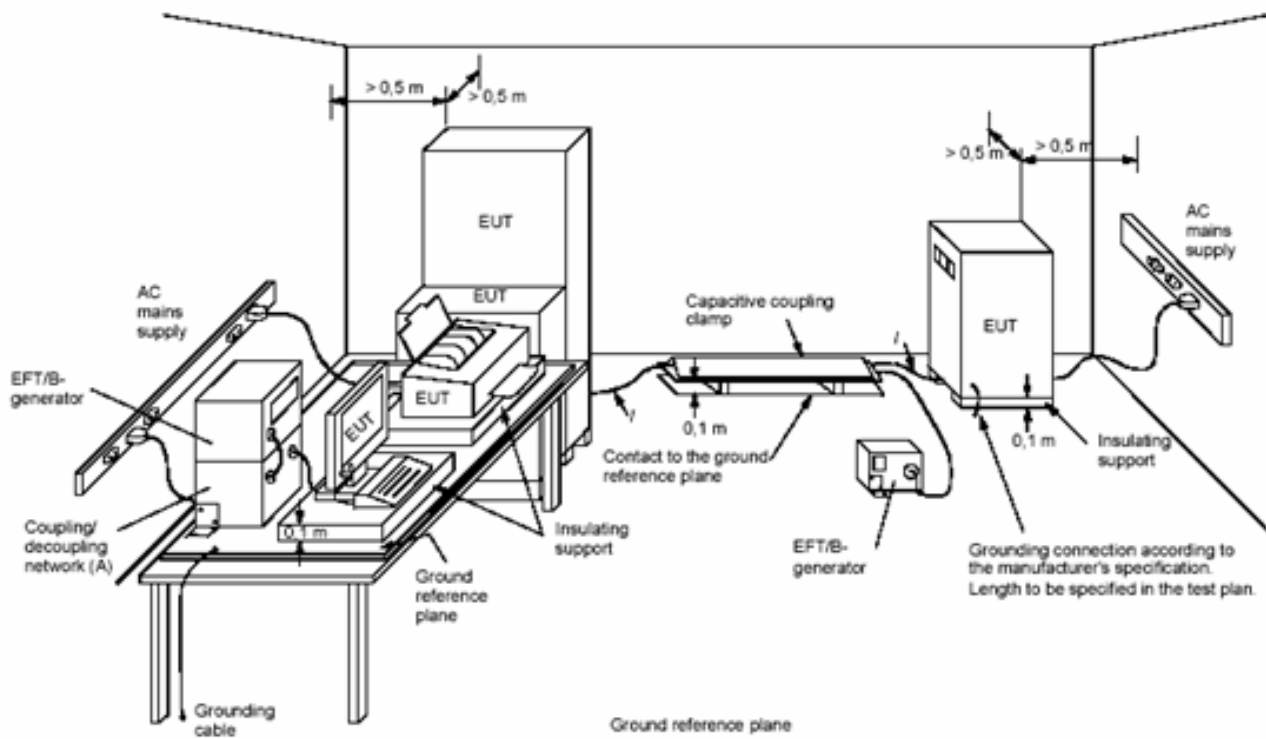


- Primjena izbijanja :
    - direktno : na EUT ,
    - indirektno: na HVP i VVP
  - Tipovi izbijanja :
    - kontaktno : na vodljive površine
    - zračeno : na izolirane površine
- 20 pražnjenja oba polariteta

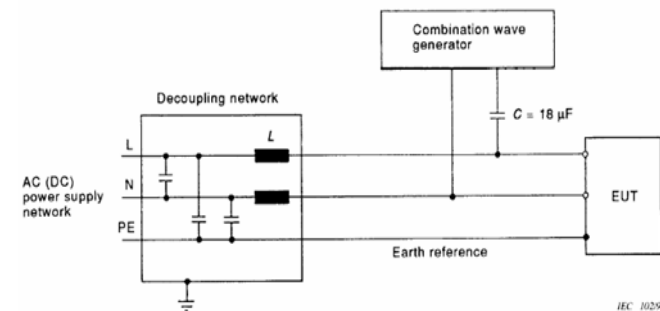
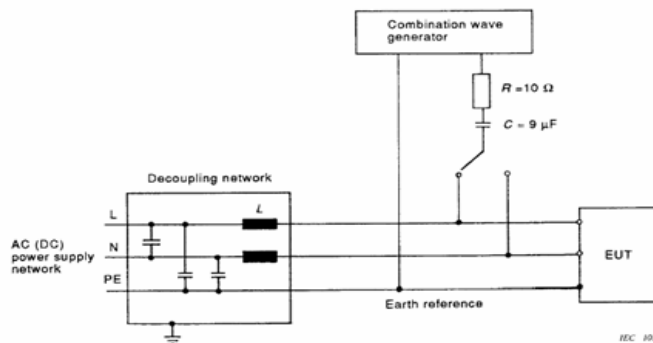
- Primjena bursta :
- istovremeno prema svim linijama,
- primjena oba polariteta
- ispitne razine : 0.5 ; 1, 2 , 4 kV
- Primjena tranzijenata u periodu od 2 min

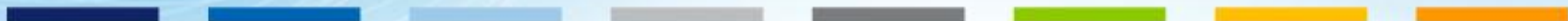
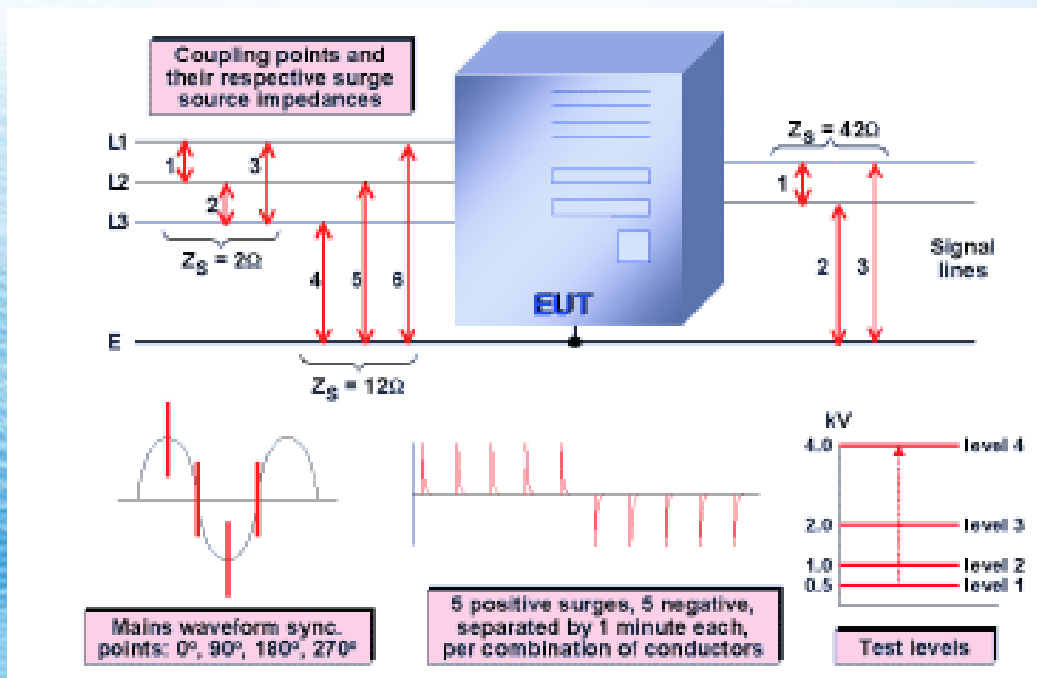






- Primjena udarnih prenapona :
- u diferencijalnom i zajedničkom modu
- primjena oba polariteta
- broj impulsa : 5,
- fazni kutevi :  $0^\circ$  ,  $90^\circ$  ,  $270^\circ$  ,
- ispitne razine : 0.5 ; 1, 2 , 4 kV







# ISPITIVANJE OTPORNOSTI NA ZRAČENA ELEKTROMAGNETSKA POLJA PREMA HRN EN 61000-4-3

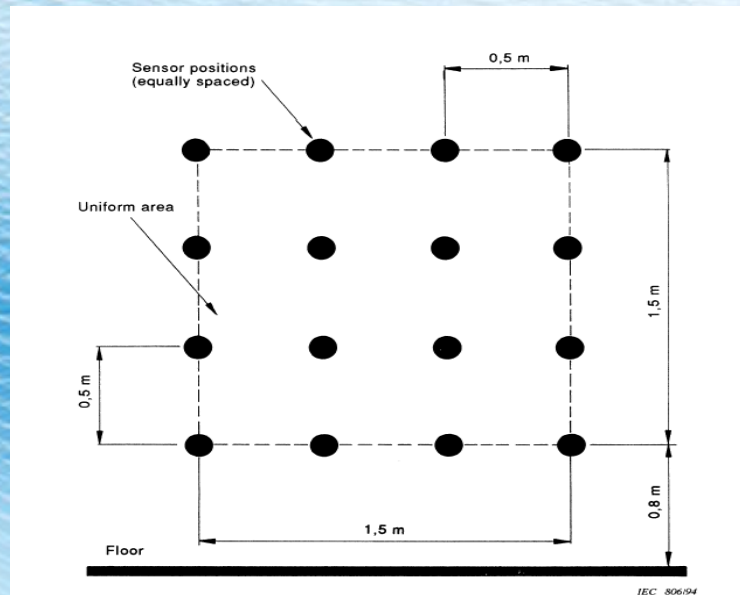
Frekvencijsko područje :

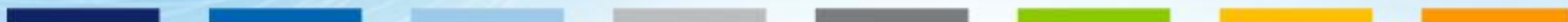
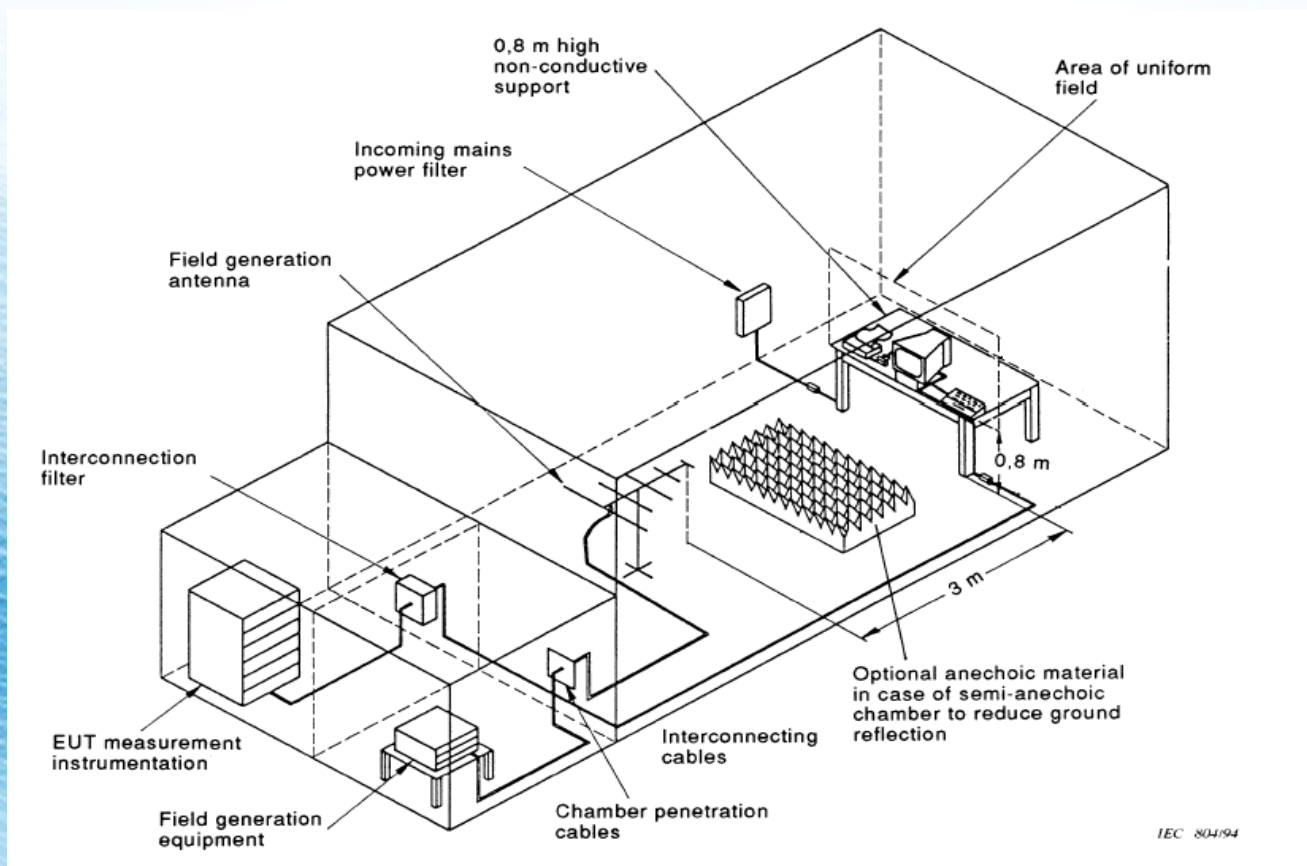
80 MHz do 1 GHz u koraku od 1 %.

1.4 GHz do 2.0 GHz u koraku od 1 %.

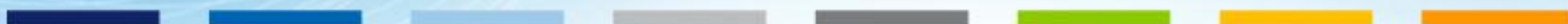
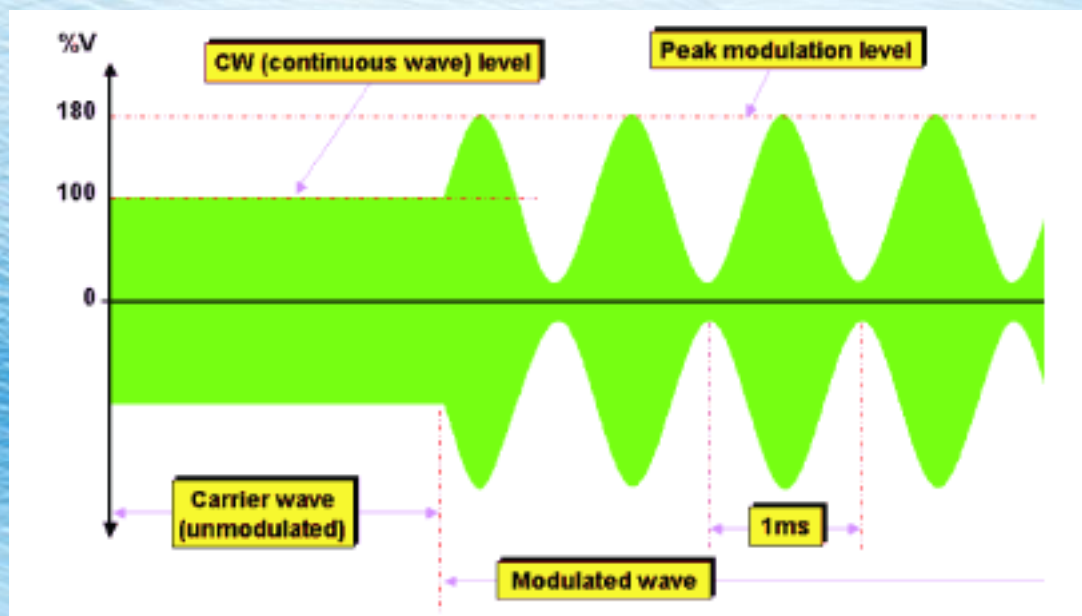
2.0 GHz do 2.7 GHz u koraku od 1 %

modulacija, 80 % na 1 kHz ili 400 Hz. ; ispitne vrijednosti : 3 V/m, 10 V/m, 1 V/m



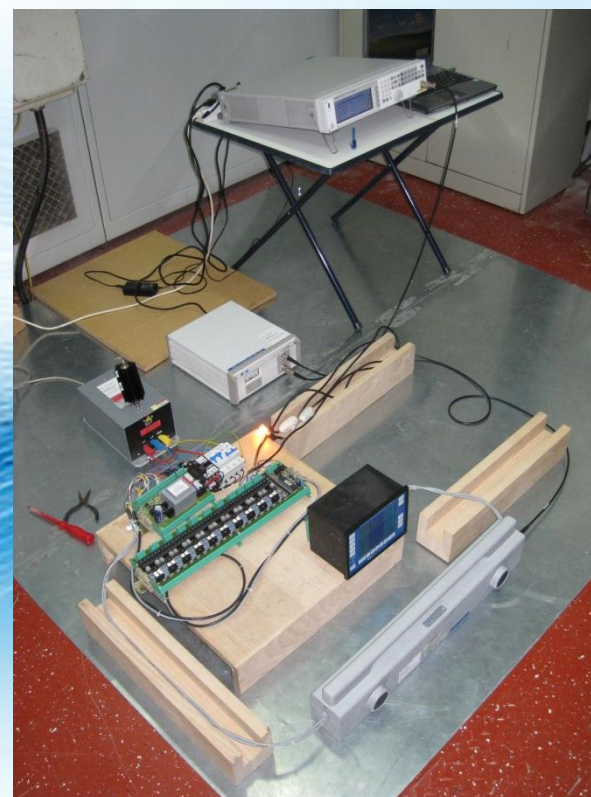
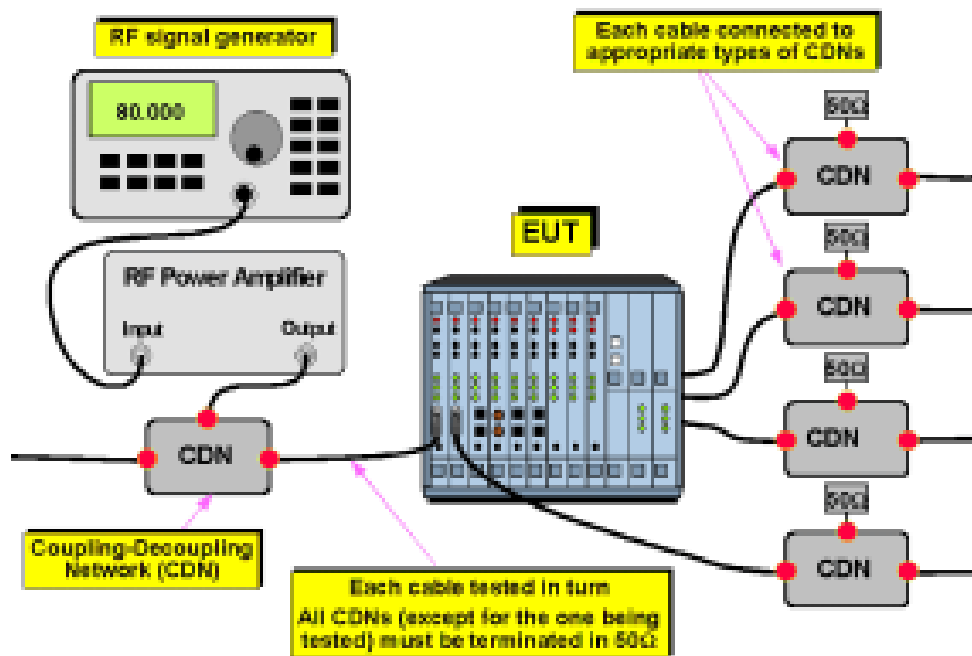


- Frekvencijsko područje : 150 kHz – 80 MHz ( 230 MHz )
- Ispitne razine napona : 1 V, 3 V , 10 V
- Valni oblik signala : AM 80 % na 1 kHz ili 400 Hz

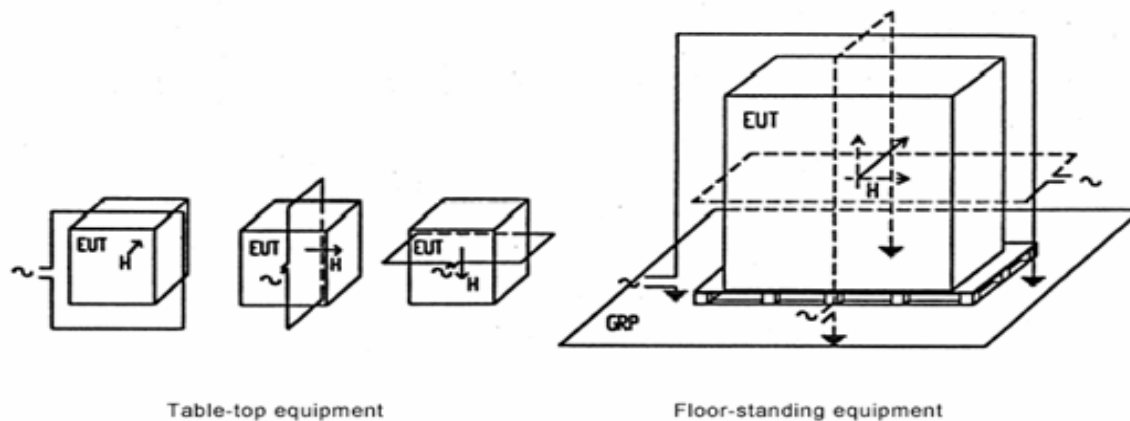




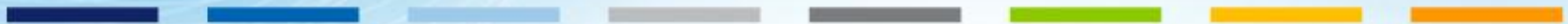
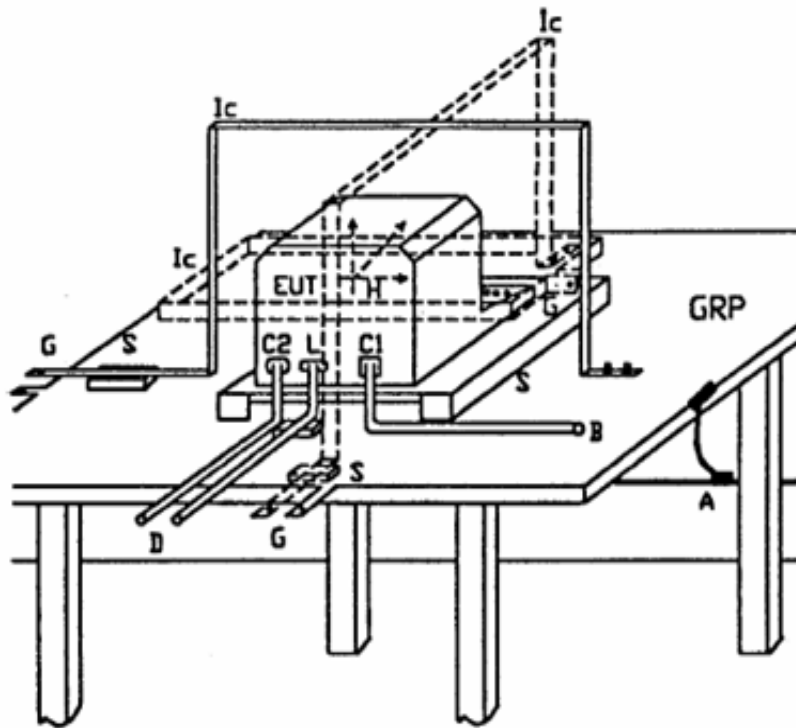
Example of a test set-up for testing multiple cable ports



- Kontinuirana primjena polja : 1 A/m, 3 A/m, 10 A/m, 30 A/m  
100 A/m
- Kratkotrajna primjena polja : 1 sekunda do 3 sekunde  
300 A/m , 1000 A/m



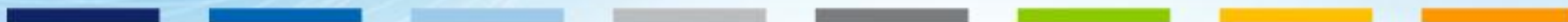
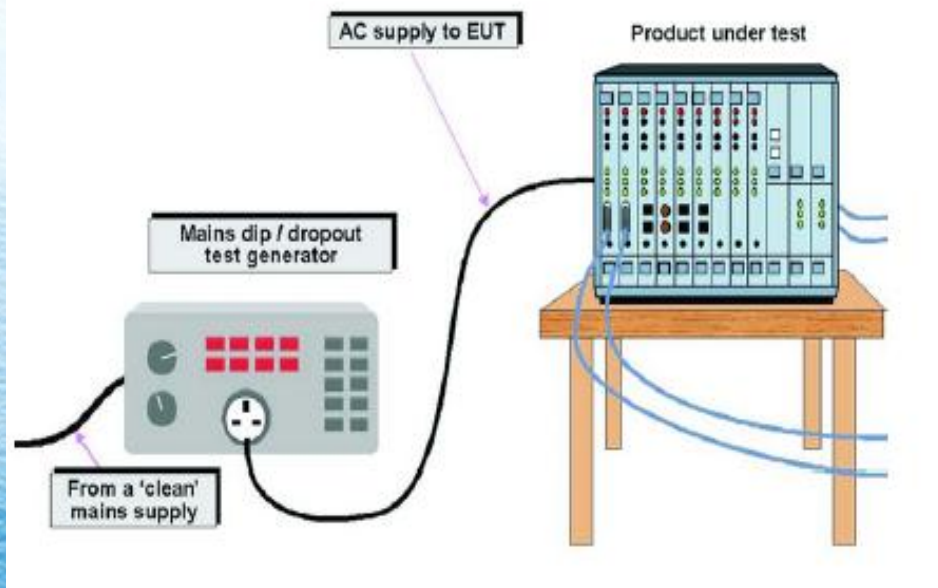
# ISPITIVANJE OTPORNOSTI NA MAGNETSKA POLJA FREKVENCije 50 Hz PREMA HRN EN 61000-4-8

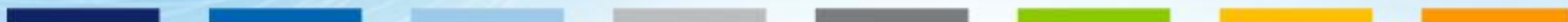
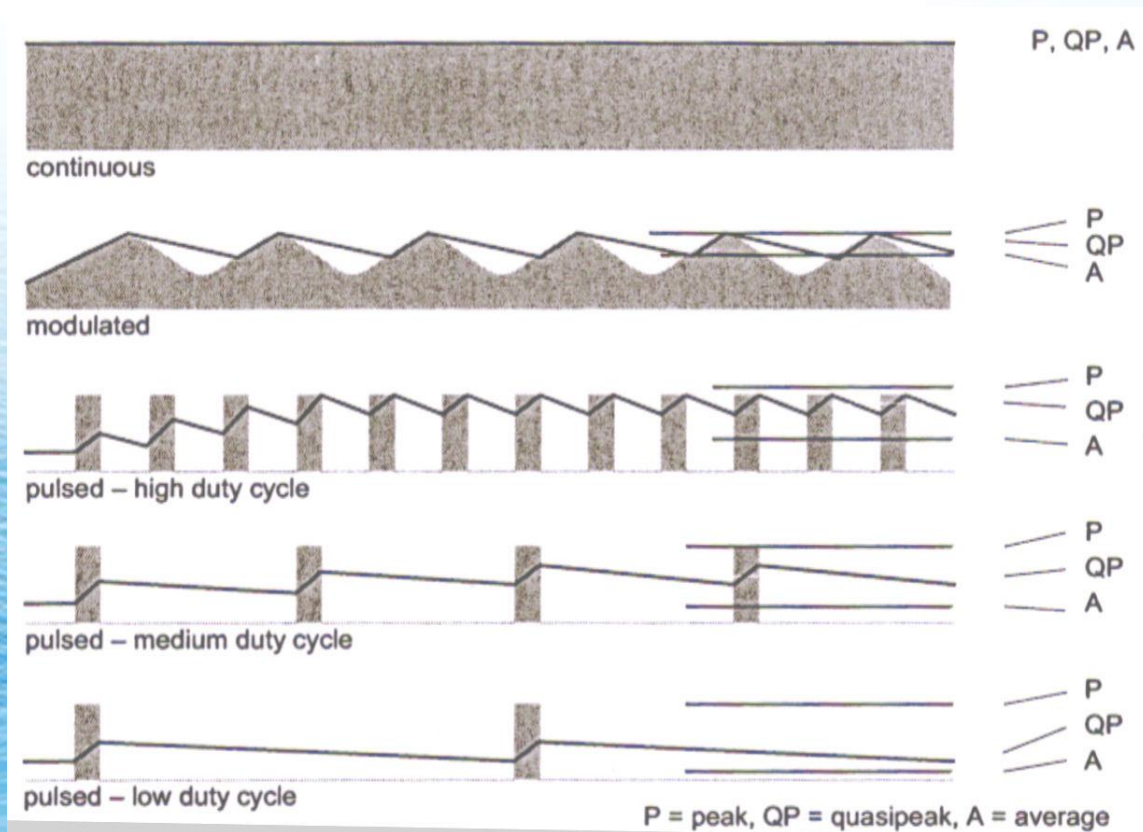




# KONČAR

## ISPITIVANJE OTPORNOSTI NA PROPADA I PREKIDE U NAPAJANJU PREMA HRN EN 61000-4-11

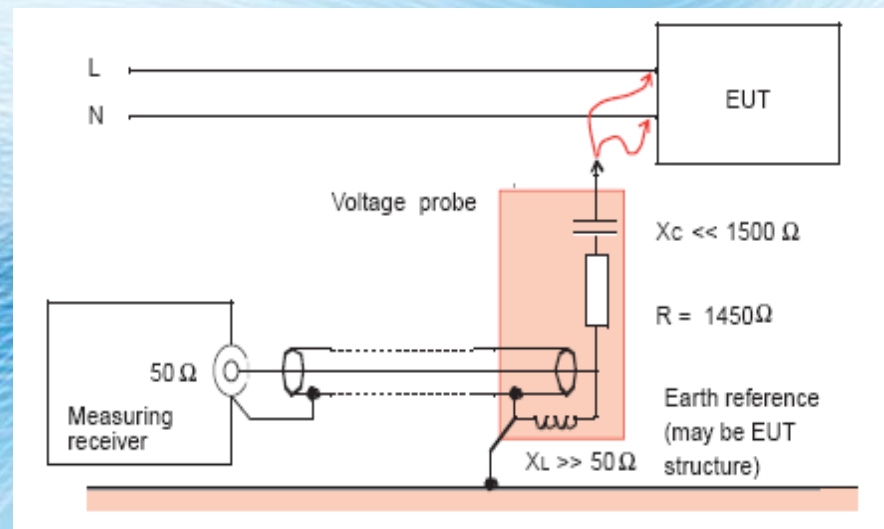
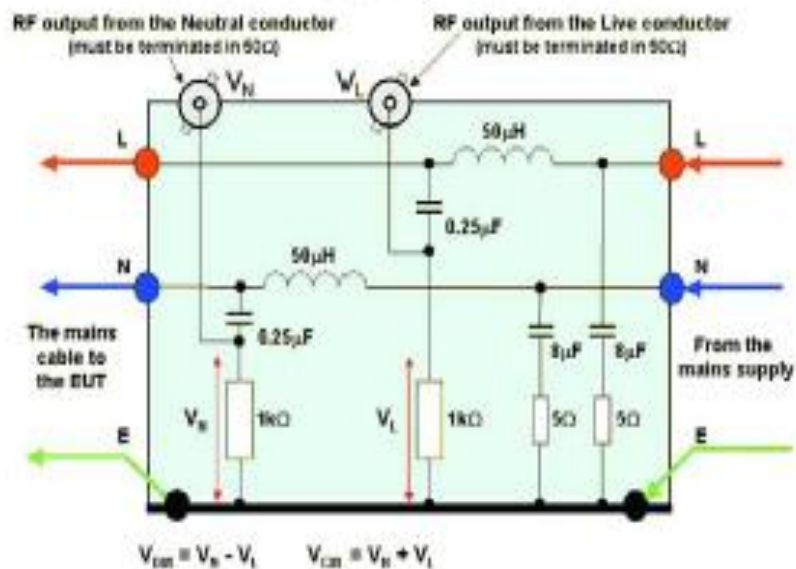




# KONČAR

## MJERENJE KONDUKTIVNIH ( VOĐENIH ) SMETNJI UMJETNA MREŽA , SONDE

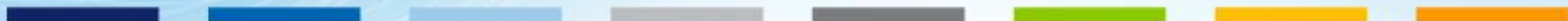
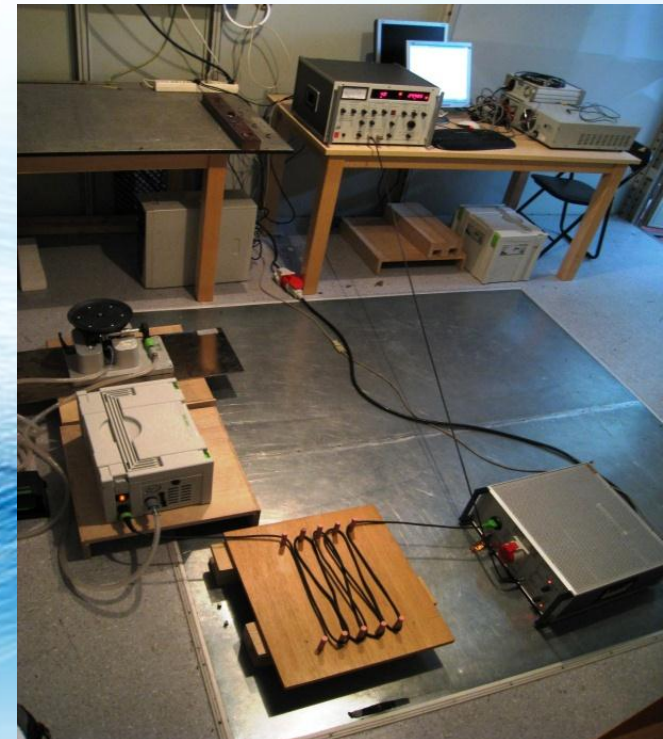
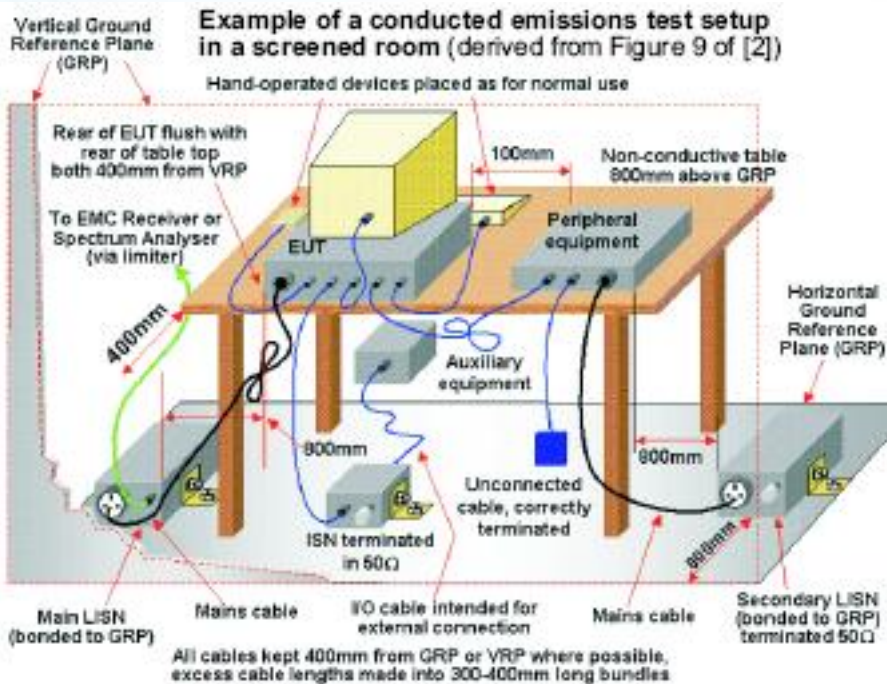
The schematic of a single-phase LISN that uses the "50Ω/50μH+5Ω" network



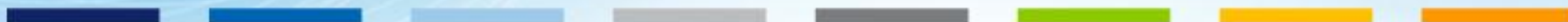
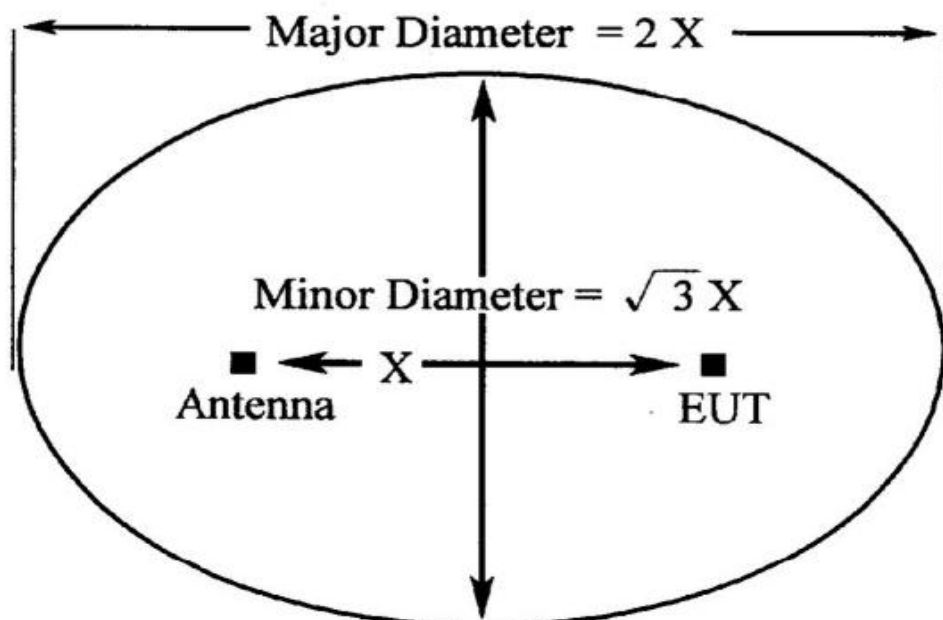


# KONČAR

## MJERENJE KONDUKTIVNIH ( VOĐENIH ) SMETNJI MJERNA KONFIGURACIJA ZA MJERENJE TRAJNIH SMETNJI



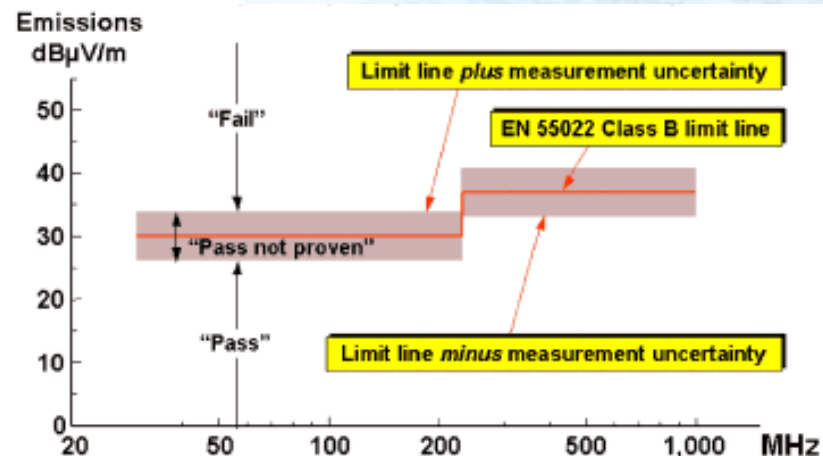
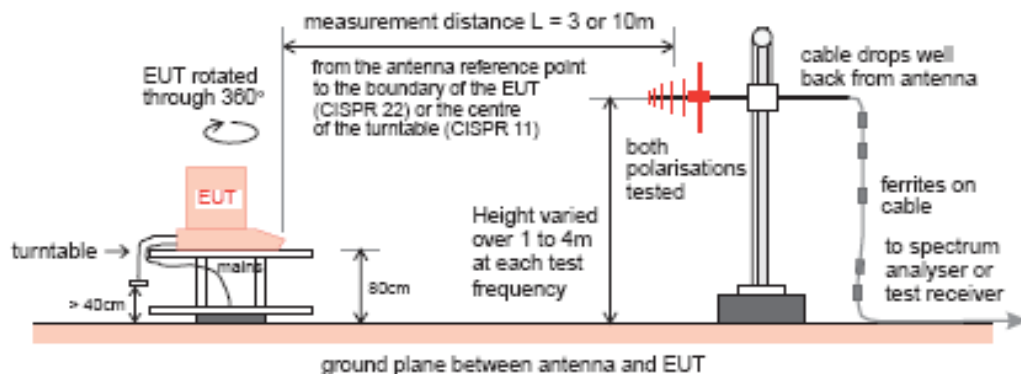
The CISPR Ellipse





# KONČAR

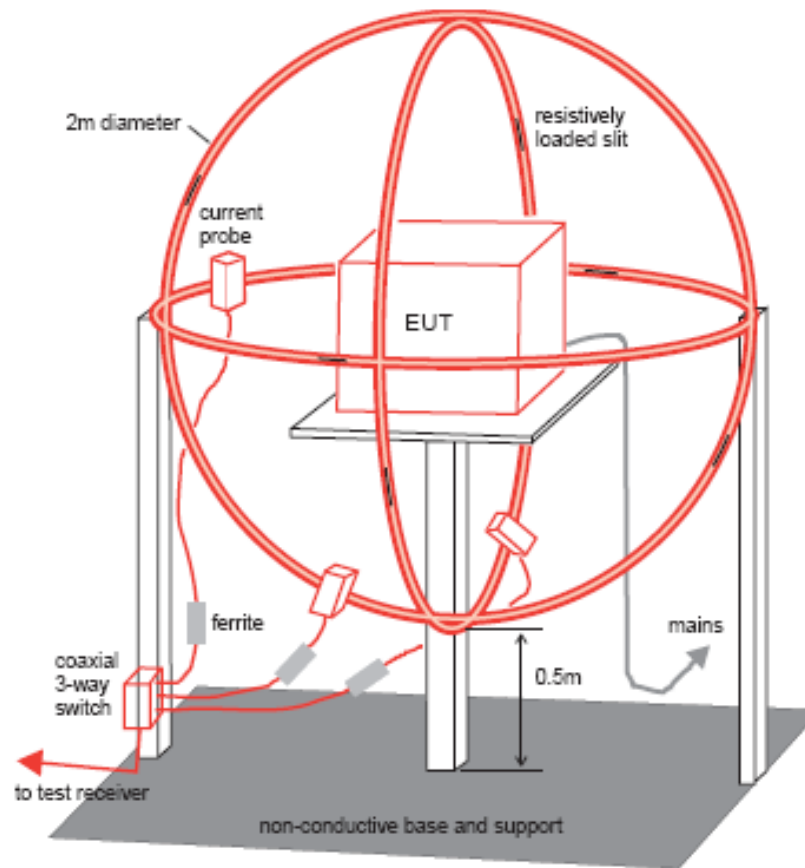
## MJERENJE ZRAČENIH SMETNJI KONFIGURACIJA MJERENJA / DOZVOLJENE VRIJEDNOSTI





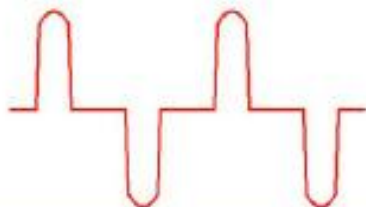
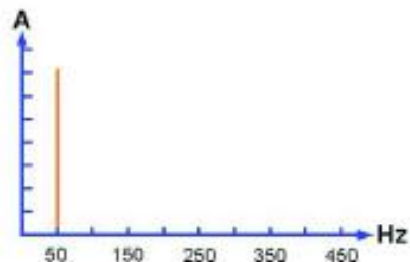
# KONČAR

## MJERENJE ZRAČENIH SMETNJI MJERENJE MAGNETSKIH POLJA / RASVJETNA TIJELA

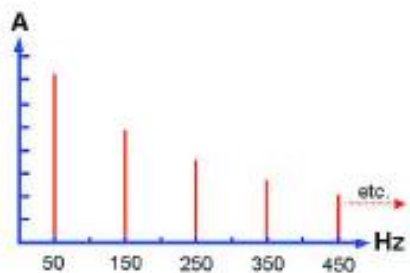


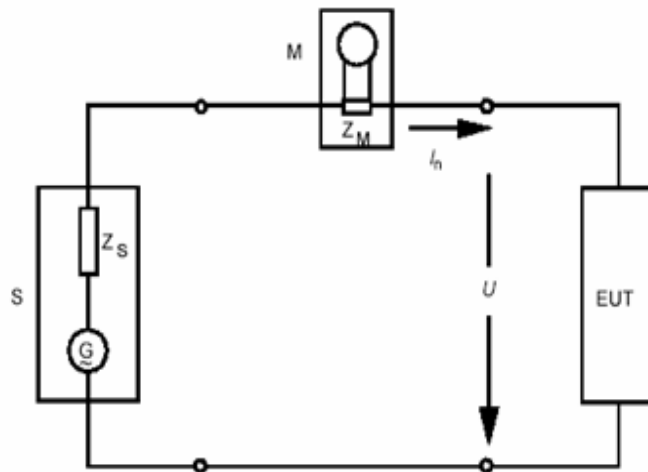


A sine-wave current



A typical non-linear current from a single-phase rectifier-capacitor power converter

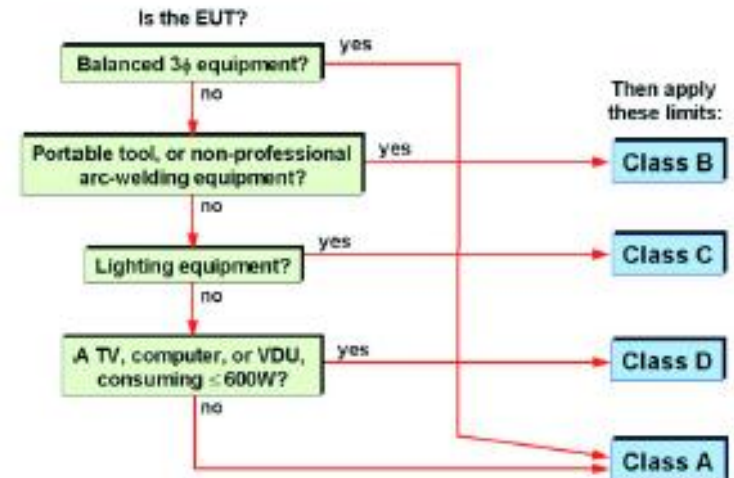




IEC 1778/2000

S power supply source  
M measurement equipment  
EUT equipment under test  
U test voltage  
 $Z_M$  input impedance of measurement equipment  
 $Z_S$  internal impedance of the supply source  
 $I_n$  harmonic component of order n of the line current  
G open-loop voltage of the supply source

### Deciding on the limits to apply





➤ **PROMJENA NAPONA**

**VOLTAGE CHANGE**

*Promjena efektivne ili vršne vrijednosti napona između dvije uzastopne razine dopuštena za konačna, ali neutvrđena trajanja*

➤ **KOLEBANJE NAPONA**

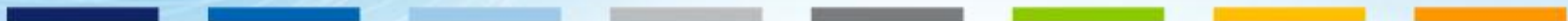
**VOLTAGE FLUCTUATION**

*Niz promjena napona ili neprekinuto mijenjanje efektivne ili vršne vrijednosti napona*

➤ **TREPERENJE**

**FLICKER**

*Utisak nestabilnosti vidnog osjeta izazvan svjetlosnim podražajem čija se svjetlina ili spektralna raspodjela mijenja s vremenom*



➤ **VRIJEDNOST KRATKOTRAJNOG TREPERENJA (  $P_{st}$  )**

**SHORT-TERM FLICKER INDIKATOR (  $P_{st}$  )**

*Mjera treperenja procijenjena u utvrđenom vremenskom razmaku razmjerno kratkog trajanja ( obično 10 minuta )*

➤ **VRIJEDNOST DUGOTRAJNOG TREPERENJA (  $P_{lt}$  )**

**LONG-TERM FLICKER INDIKATOR (  $P_{lt}$  )**

*Mjera treperenja procijenjena u utvrđenom vremenskom razmaku razmjerno dugog trajanja, s pomoću uzastopnih vrijednosti kratkotrajnog treperenja ( obično 120 minuta )*

